

# (19) United States

# (12) Patent Application Publication (10) Pub. No.: US 2023/0231574 A1 Schaefer

Jul. 20, 2023 (43) **Pub. Date:** 

### SYNDROME CHECK FUNCTIONALITY TO DIFFERENTIATE BETWEEN ERROR TYPES

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Appl. No.: 18/098,995

(22) Filed: Jan. 19, 2023

### Related U.S. Application Data

(60)Provisional application No. 63/301,320, filed on Jan. 20, 2022.

#### **Publication Classification**

(51)Int. Cl. (2006.01)H03M 13/11 H03M 13/43 (2006.01) H03M 13/00 (2006.01) (52) U.S. Cl. CPC ...... H03M 13/1111 (2013.01); H03M 13/43 (2013.01); H03M 13/611 (2013.01)

#### (57)**ABSTRACT**

Methods, systems, and devices for syndrome check functionality to differentiate between error types are described. A host system, a memory system, or some combination of both may include syndrome check circuitry to provide enhanced error diagnostic capabilities for data communicated between the host system and the memory system. The syndrome check circuitry may receive a first signal from the memory system indicating whether the memory system detected and attempted to correct an error in the data and may receive a second signal from the host system indicating whether the host system detected an error in the received data. The syndrome check circuitry may compare the first signal and the second signal using a set of logic gates to differentiate between different combinations of errors detected at one or both of the memory system or the host system.

